IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

MAR re Application of:

1994 Steve W. Heppler

MANUAL No.: 08/046,246

Filed: April 13, 1993

For: METHOD AND APPARATUS FOR TESTING OPENS AND SHORTS

ON INTEGRATED CIRCUITS

COMING OFF OF A SINGULATION STATION

Docket No.: 92-476

Paper No.: 4

Group Art Unit: 3101

Examiner: T. Nguyen

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92-476

March 18, 1994

Commissioner of Patents and Trademarks Washington, D.C. 20231

Dear Commissioner:

AMENDMENT

In response to the Examiner's outstanding Office Action, mailed December 21, 1993, please amend the application as follows:

In the Title:

Kindly change the Title to the following:
-- METHOD AND APPARATUS FOR TESTING AN INTEGRATED CIRCUIT --.

<u>In the abstract:</u>

On line 4 after "IC" please insert -- (integrated circuit) --.

In the specification:

Page 3, line 8, after invention kindly insert the following paragraph:

-- The invention is a method and an apparatus for controlling positioning of a circuit before, during and after a circuit

Micron Semiconductor, Inc.

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